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TITLE: Inspecting Optical Masks With Electron Beam Microscopy

EXAMINER: Unknown

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**CERTIFICATE OF MAILING**

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By: \_\_\_\_\_  
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PRELIMINARY AMENDMENT

Sir:

This application is a continuation of pending application number 09/502,534, filed on February 10, 2000, which was a reissue application for patent no. 5,717,204 issued February 10, 1998, which is a continuation of 08/252,763, which is a CIP of 07/889,460, and is in response to the Notice of Appeal filed August 14, 2003, which established a non-statutory period for filing an

appellate brief that expired on March 14, 2004 (a Sunday). A fee for a five-month extension of time is included herewith.